

Notice of References Cited	Application/Control No. 10/726,876		Applicant(s)/Patent Under Reexamination KADOWAKI ET AL.	
	Examiner Yuzhen Ge		Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,661,927 b1	12-2003	Suarez et al.	382/240
*	C	US-7,076,104 b1	07-2006	Keith et al.	382/233
*	D	US-7,006,576 b1	02-2006	Hannuksela, Miska	375/240.27
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*	H	US-5,416,604	05-1995	Park, Goo-man	382/232
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sections 6-7, Annex D.5, J.7 and J.14, ISO/IEC 15444-1, 1st Edition, 2000-12-15, hereafter referred to as 15444-1
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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